

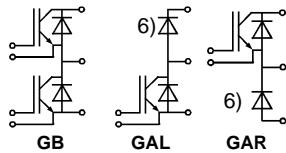
Absolute Maximum Ratings		Values		Units
Symbol	Conditions ¹⁾			
V _{CES}		1200		V
V _{CGR}	R _{GE} = 20 kΩ	1200		V
I _C	T _{case} = 25/80 °C	100 / 75		A
I _{CM}	T _{case} = 25/80 °C; t _p = 1 ms	200 / 150		A
V _{GES}		± 20		V
P _{tot}	per IGBT, T _{case} = 25 °C	625		W
T _j , (T _{stg})		- 40 ... +150 (125)		°C
V _{isol}	AC, 1 min.	2 500 ⁷⁾		V
humidity	DIN 40 040	Class F		
climate	DIN IEC 68 T.1	55/150/56		
Inverse Diode		FWD ⁶⁾		
I _F = - I _C	T _{case} = 25/80 °C	95 / 65	130 / 90	A
I _{FM} = - I _{CM}	T _{case} = 25/80 °C; t _p = 1 ms	200 / 150	200 / 150	A
I _{FSM}	t _p = 10 ms; sin.; T _j = 150 °C	720	1100	A
I _{2t}	t _p = 10 ms; T _j = 150 °C	2600	6000	A ² s

SEMITRANS® M IGBT Modules

SKM 100 GB 123 D ⁶⁾
SKM 100 GAL 123 D ⁶⁾
SKM 100 GAR 123 D ⁶⁾



SEMITRANS 2



Characteristics		Units		
Symbol	Conditions ¹⁾	min.	typ.	max.
V _{(BR)CES}	V _{GE} = 0, I _C = 4 mA	≥ V _{CES}	—	—
V _{GE(th)}	V _{GE} = V _{CE} , I _C = 2 mA	4,5	5,5	6,5
I _{CES}	V _{GE} = 0 T _j = 25 °C V _{CE} = V _{CES} T _j = 125 °C	— —	0,1 6	1,5 mA
I _{GES}	V _{GE} = 20 V, V _{CE} = 0	—	—	300 nA
V _{CESsat}	I _C = 75 A V _{GE} = 15 V; I _C = 100 A T _j = 25 (125) °C	— —	2,5(3,1) 2,8(3,6)	3(3,7) V
V _{CESsat}	V _{CE} = 20 V, I _C = 75 A	31	—	— S
C _{CHC}	per IGBT	—	—	350 pF
C _{ies}	V _{GE} = 0	—	5	6,6 nF
C _{oes}	V _{CE} = 25 V	—	720	900 pF
C _{res}	f = 1 MHz	—	380	500 pF
L _{CE}		—	—	30 nH
t _{d(on)}	V _{CC} = 600 V	—	30	60 ns
t _r	V _{GE} = +15 V, - 15 V ³⁾	—	70	140 ns
t _{d(off)}	I _C = 75 A, ind. load	—	450	600 ns
t _f	R _{Gon} = R _{Goff} = 15 Ω	—	70	90 ns
E _{on} ⁵⁾	T _j = 125 °C	—	10	— mWs
E _{off} ⁵⁾		—	8	— mWs
Inverse Diode ⁸⁾				
V _F = V _{EC}	I _F = 75 A V _{GE} = 0 V;	—	2,0(1,8)	2,5 V
V _F = V _{EC}	I _F = 100 A T _j = 25 (125) °C	—	2,25(2,05)	— V
V _{TO}	T _j = 125 °C	—	—	1,2 V
T _T	T _j = 125 °C	—	12	15 mΩ
I _{RRM}	I _F = 75 A; T _j = 25 (125) °C ²⁾	—	27(40)	— A
Q _{rr}	I _F = 75 A; T _j = 25 (125) °C ²⁾	—	3(10)	— μC
FWD of types "GAL", "GAR" ⁸⁾				
V _F = V _{EC}	I _F = 75 A V _{GE} = 0 V;	—	1,85(1,6)	2,2 V
V _F = V _{EC}	I _F = 100 A T _j = 25 (125) °C	—	2,0(1,8)	— V
V _{TO}	T _j = 125 °C	—	—	1,2 V
T _T	T _j = 125 °C	—	9	11 mΩ
I _{RRM}	I _F = 75 A; T _j = 25 (125) °C ²⁾	—	30(45)	— A
Q _{rr}	I _F = 75 A; T _j = 25 (125) °C ²⁾	—	3,5(11)	— μC
Thermal Characteristics				
R _{thjc}	per IGBT	—	—	0,2 °C/W
R _{thjc}	per diode / FWD "GAL; GAR"	—	—	0,50/0,36 °C/W
R _{thch}	per module	—	—	0,05 °C/W

¹⁾ T_{case} = 25 °C, unless otherwise specified

²⁾ I_F = - I_C, V_R = 600 V, - dI/dt = 800 A/μs, V_{GE} = 0 V

³⁾ Use V_{GEoff} = -5 ... -15 V

⁵⁾ See fig. 2 + 3; R_{Goff} = 15 Ω

⁶⁾ The free-wheeling diodes of the GAL and GAR types have the data of the inverse diodes of SKM 150 GB 123 D

⁷⁾ V_{isol} = 4000 V_{rms} on request

⁸⁾ CAL = Controlled Axial Lifetime Technology.

Cases and mech. data → B6 - 46

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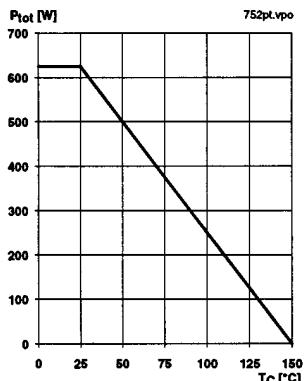


Fig. 1 Rated power dissipation $P_{tot} = f(T_c)$

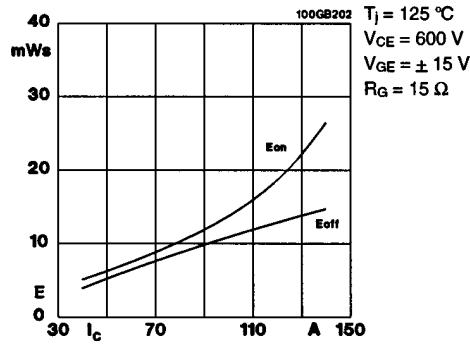


Fig. 2 Turn-on /-off energy = f (I_c)

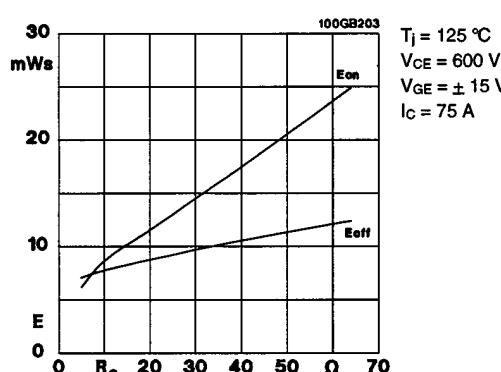


Fig. 3 Turn-on /-off energy = f (R_g)

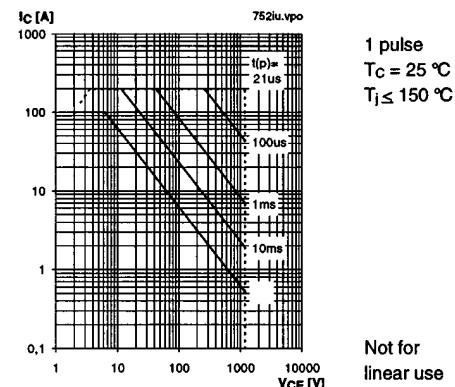


Fig. 4 Maximum safe operating area (SOA) $I_c = f(V_{CE})$

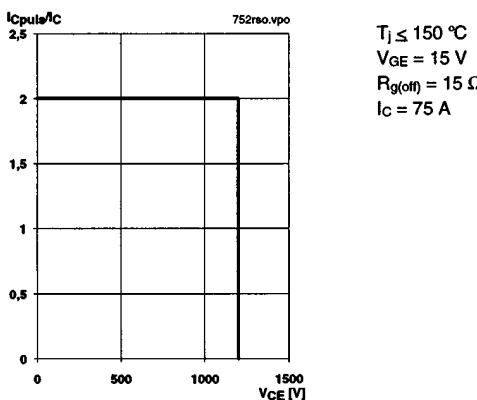


Fig. 5 Turn-off safe operating area (RBSOA)

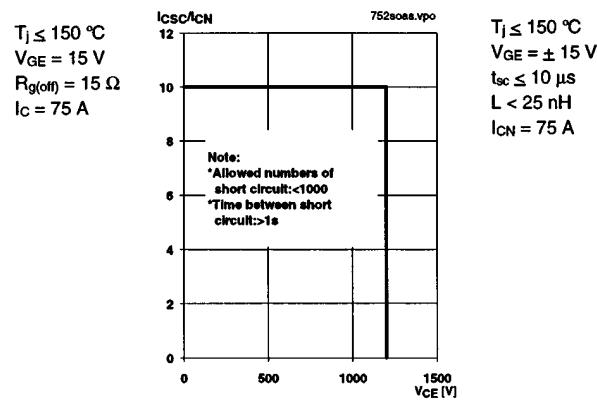


Fig. 6 Safe operating area at short circuit $I_c = f(V_{CE})$

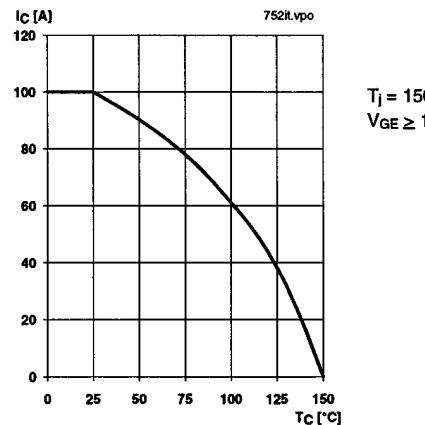


Fig. 8 Rated current vs. temperature $I_c = f(T_c)$

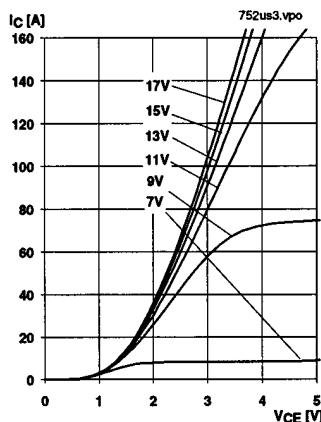


Fig. 9 Typ. output characteristic, $t_p = 80 \mu\text{s}; 25 \text{ }^{\circ}\text{C}$

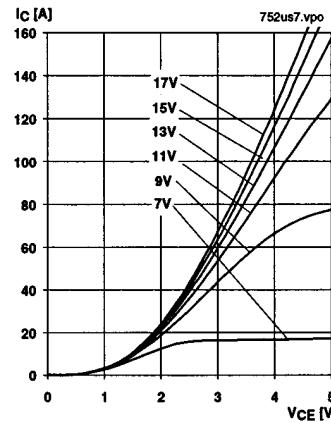


Fig. 10 Typ. output characteristic, $t_p = 80 \mu\text{s}; 125 \text{ }^{\circ}\text{C}$

$$P_{cond}(t) = V_{CEsat}(t) \cdot I_C(t)$$

$$V_{CEsat}(t) = V_{CE(TO)(T)} + r_{CE}(T) \cdot I_C(t)$$

$$V_{CE(TO)(T)} \leq 1,5 + 0,002 (T_J - 25) \text{ [V]}$$

$$r_{CE}(T) = 0,013 + 0,00006 (T_J - 25) \text{ [\Omega]}$$

valid for $V_{GE} = + 15 \frac{+2}{-1} \text{ [V]}$; $I_C > 0,3 I_{Cnom}$

Fig. 11 Typ. saturation characteristic (IGBT)
Calculation elements and equations

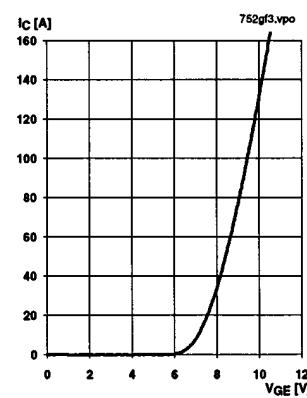


Fig. 12 Typ. transfer characteristic, $t_p = 80 \mu\text{s}; V_{CE} = 20 \text{ V}$

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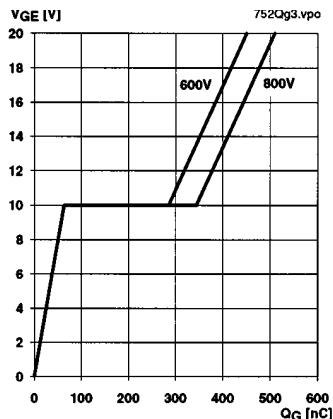


Fig. 13 Typ. gate charge characteristic

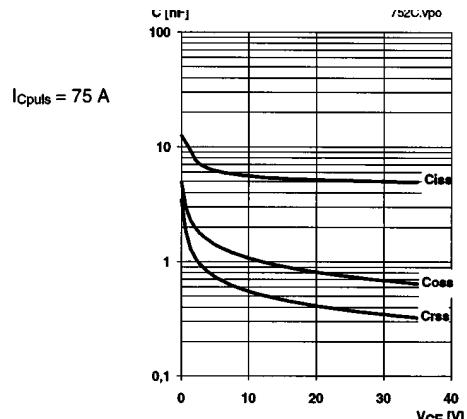


Fig. 14 Typ. capacitances vs. V_{CE}

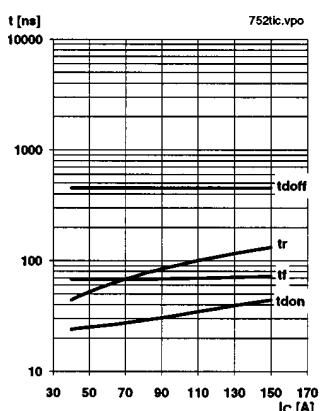


Fig. 15 Typ. switching times vs. I_C

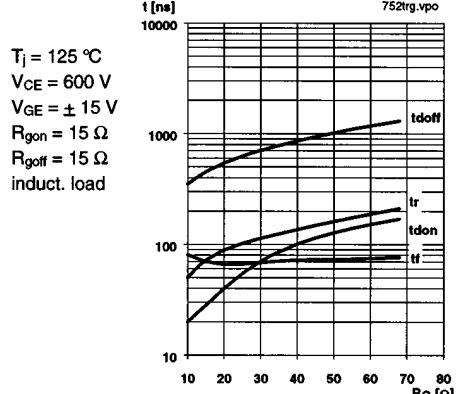


Fig. 16 Typ. switching times vs. gate resistor R_G

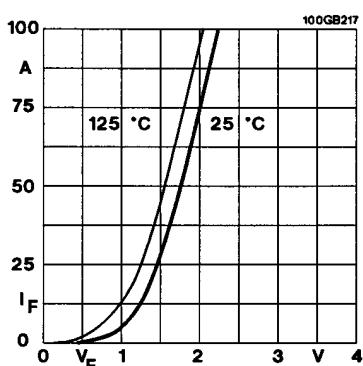


Fig. 17 Typ. CAL diode forward characteristic

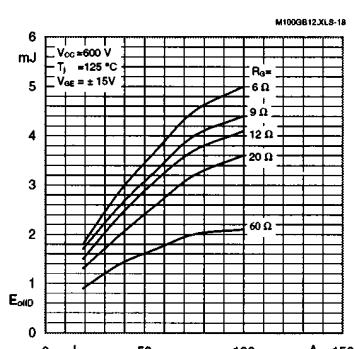


Fig. 18 Diode turn-off energy dissipation per pulse

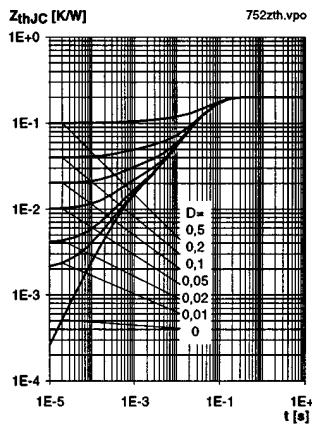


Fig. 19 Transient thermal impedance of IGBT
 $Z_{thJC} = f(t_p); D = t_p / t_c = t_p \cdot f$

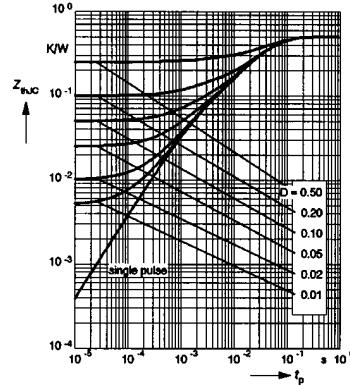


Fig. 20 Transient thermal impedance of
 $inverse CAL diodes Z_{thJC} = f(t_p); D = t_p / t_c = t_p \cdot f$

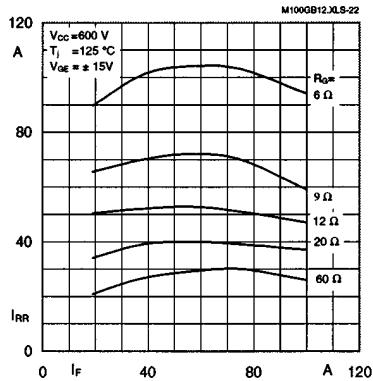


Fig. 22 Typ. CAL diode peak reverse recovery current $I_{RR} = f(I_F; R_G)$

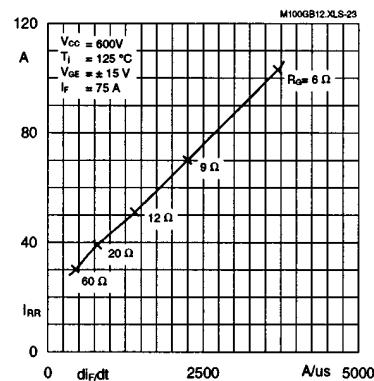


Fig. 23 Typ. CAL diode peak reverse recovery current $I_{RR} = f(dI/dt)$

Typical Applications include
 Switched mode power supplies
 DC servo and robot drives
 Inverters
 DC choppers (versions GAR; GAL)
 AC motor speed control
 Inductive heating
 UPS Uninterruptable power supplies
 General power switching applications
 Electronic (also portable) welders
 Pulse frequencies also above 15 kHz

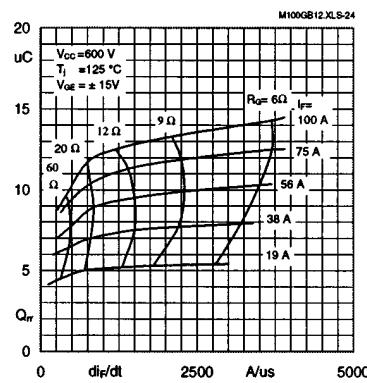
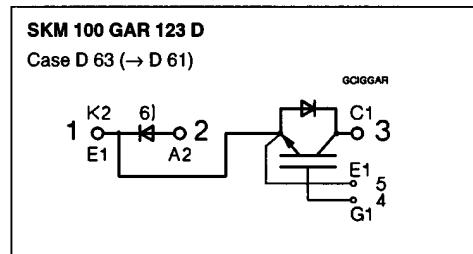
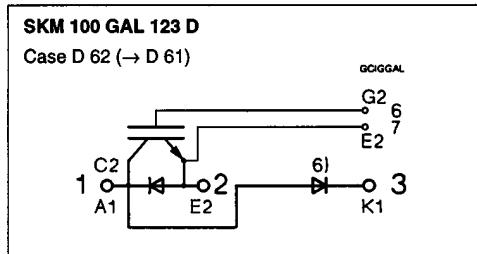
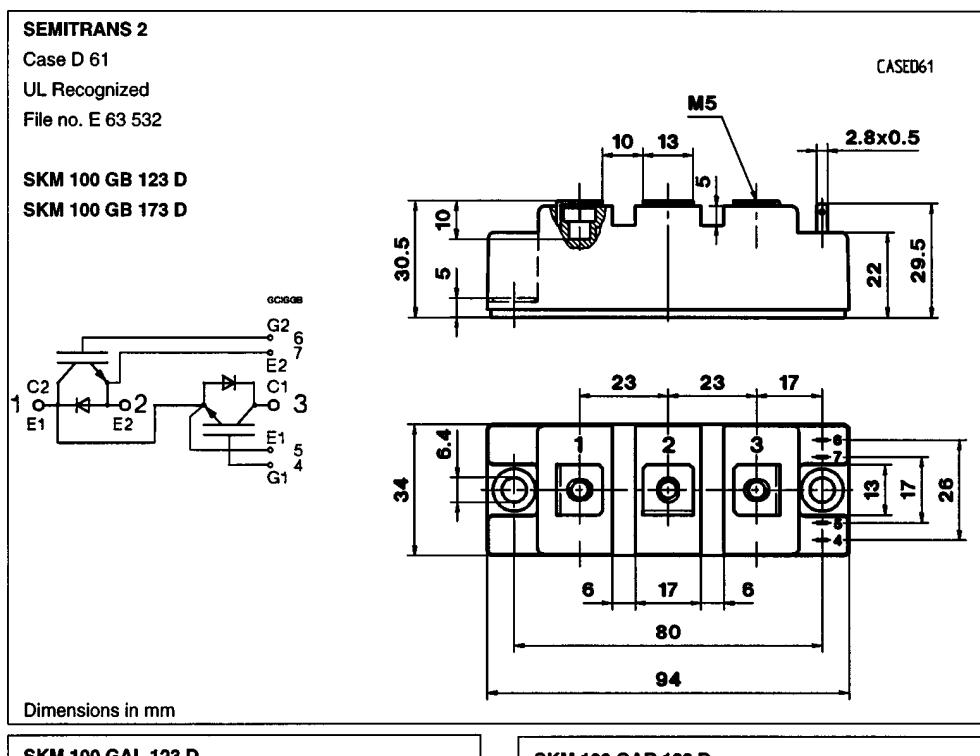


Fig. 24 Typ. CAL diode recovered charge $Q_{rr} = f(dI/dt)$

SKM 100 GB 123 D ...



Case outline and circuit diagrams

Symbol	Conditions	Values			Units
		min.	typ.	max.	
M ₁	to heatsink, SI Units to heatsink, US Units	(M6)	3 27	— 44	Nm lb.in.
M ₂	for terminals, SI Units for terminals US Units	(M5)	2,5 22	— 44	Nm lb.in.
a		—	—	5x9,81	m/s ²
w		—	—	250	g

This is an electrostatic discharge sensitive device (ESDS). Please observe the international standard IEC 747-1, Chapter IX.

Eight devices are supplied in one SEMIBOX A without mounting hardware, which can be ordered separately under Ident No. 33321100 (for 10 SEMITRANS 2). Larger packing units of 20 and 42 pieces are used if suitable.
Accessories \rightarrow page B 6 - 4.
SEMIBOX \rightarrow page C - 1.

⁶⁾ Freewheeling diode \rightarrow page B 6 - 41, remark 6.